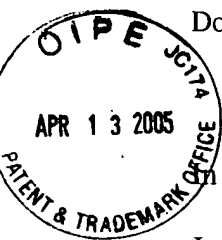


JPW

Docket No.: 87353.2980

PATENT



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

James C. ALEXANDER, et al.

Serial No. 10/664,971

Filed: September 22, 2003

:  
:  
:  
:  
: Group Art Unit: 3671  
:  
: Examiner: Raymond W. Addie

For: SPRING COUNTERBALANCE METHOD AND APPARATUS FOR VARIABLY  
BIASING A DOCK LEVELER

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

These references were cited in the International Search Report dated 18 February 2005. No further elaboration is believed necessary. Copies of the search report and cited art are submitted herewith in accordance with 37 C.F.R. 1.98(a).

AUTHORIZATION

No fee is required. The Commissioner is hereby authorized to charge any additional fees which may be required for this submission, or credit any overpayment to deposit account no. 50-2036.

Respectfully submitted,

BAKER & HOSTETLER LLP



Kenneth J. Sheehan  
Registration No. 36,270

Date: April 13, 2005  
Baker & Hostetler LLP  
Washington Square, Suite 1100  
1050 Connecticut Avenue, N.W.  
Washington, D.C. 20036  
Telephone: (202) 861 1500  
Facsimile: (202) 861 1783

Docket No.: 87353.2980

PATENT

## LIST OF ART CITED BY APPLICANT

(PTO-1449)

ATTY. DOCKET NO.  
87353.2980SERIAL NO.  
10/664,971APPLICANT  
James C. ALEXANDER, et al.FILING DATE  
September 22, 2003GROUP  
3671

## U.S. PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A		3,766,585	10/23/73	Yoon	14	72	4/27/71
B		3,639,935	2/8/72	Kumpolt	14	72	6/15/70
7							
D							
E							
F							
G							
H							
I							
J							
K							
L							
M							
N							
O							
P							
Q							
R							
S							
T							

## FOREIGN PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
U							
V							
W							
X							
Y							
Z							
AA							
BB							
CC							
DD							
EE							
FF							
GG							

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

HH		
II		
JJ		
KK		
LL		
MM		
NN		

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

